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| Notice of References Cited | Application/Control No. 10/046,222 | Applicant(s)/Patent Under Reexamination DOE, STEVEN | |
| | Examiner XIAO M. WU | Art Unit 2674 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-5,406,305 | 04-1995 | Shimomura et al. | 345/102 |
| | B | US-6,094,185 | 07-2000 | Shirriff, Kenneth W. | 345/102 |
| | C | US-6,362,822 | 03-2002 | Randel, Mark R. | 345/426 |
| | D | US-6,481,851 | 11-2002 | McNelley et al. | 353/28 |
| | E | US-6,611,249 | 08-2003 | Evanicky et al. | 345/102 |
| | F | US-6,614,498 | 09-2003 | Tanaka et al. | 349/143 |
| | G | US-2002/0176113 | 11-2002 | Edgar, Albert D. | 358/3.27 |
| | H | US-2004/0071366 | 04-2004 | Zhang et al. | 382/284 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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